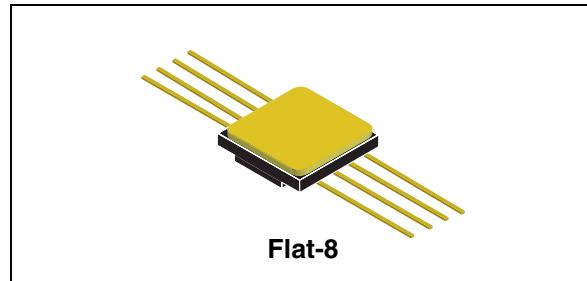


## Rad-tolerant current mode PWM controller

### Features

- Oscillator frequency guaranteed at 250 kHz
- Trimmed oscillator for precise frequency control
- Current mode operation to 500 kHz automatic feed forward compensation
- Latching PWM for cycle-by-cycle current limiting
- Internally trimmed reference with undervoltage lockout
- High current totem pole output
- Undervoltage lockout with hysteresis
- Low start-up and operating current
- Hermetic package
- 50 and 100 krad (Si)
- SEL free @ 120 MeV/cm<sup>2</sup>/mg at 125°C



### Description

The ST1843HR and ST1845HR ICs are rad-tolerant current mode PWM controllers providing an industry standard solution for the implementation of provides the off-line or DC to DC fixed frequency current mode control schemes with a minimal external parts count.

Its radiation hardness and hermetic packaging makes it an ideal choice for aerospace and other harsh environments.

**Table 1. Device summary**

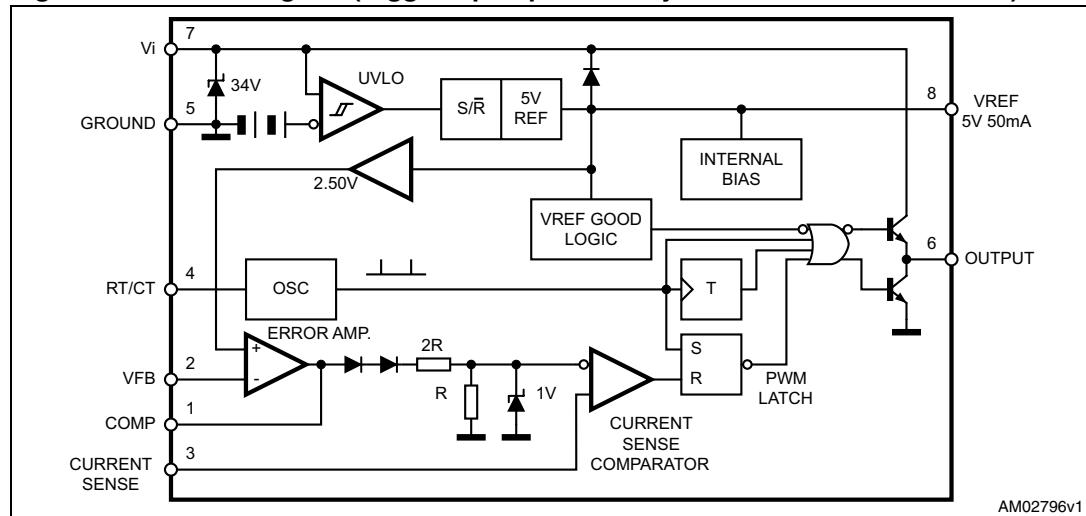
Order codes	Duty cycle max	Radiation level	Quality level	EPPL	Package	Lead finish	Mass (g)
ST1843K1	100%	50 krad (Si)	Engineering Model	-	Flat-8	Gold	0.45
ST1843FKG	100%	50 krad (Si)	According to ESCC	Target	Flat-8	Gold	0.45
ST1845K1	50%	100 krad (Si)	Engineering Model	-	Flat-8	Gold	0.45
ST1845RKG	50%	100 krad (Si)	According to ESCC	Target	Flat-8	Gold	0.45

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# 1 Block diagram

Figure 1. Block diagram (toggle flip flop used only in UC3844B and UC3845B)



## 2 Maximum ratings

**Table 2. Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_i$	Supply voltage (low impedance source)	30	V
	Supply voltage ( $I_i < 30\text{mA}$ )	Self limiting	
$I_o$	Output current	$\pm 1$	A
$E_o$	Output energy (capacitive load)	5	mJ
	Analog inputs (pins 2, 3)	-0.3 to 5.5	V
	Error amplifier output sink current	10	mA
$P_{tot}$	Power dissipation at $T_A \leq 25^\circ\text{C}$ (SO8)	800	mW
$T_{stg}$	Storage temperature range	-65 to 150	$^\circ\text{C}$
$T_J$	Junction operating temperature	-40 to 150	$^\circ\text{C}$

*Note:* All voltages are with respect to pin 5, all currents are positive into the specified terminal.

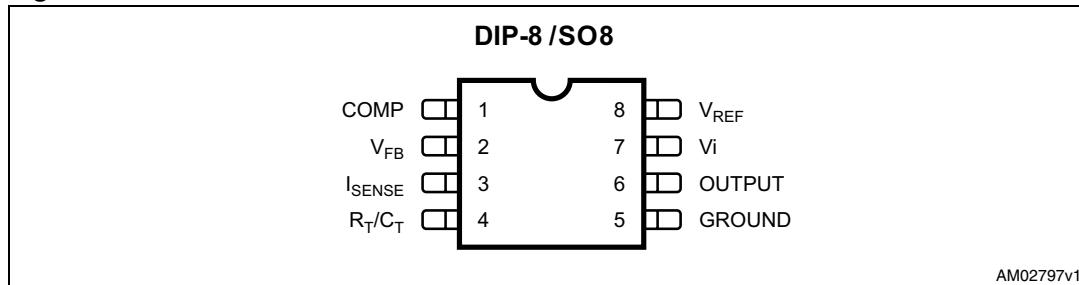
## 3 Thermal data

**Table 3. Thermal data**

Symbol	Description	Flat-8	Unit
$R_{thJA}$	Thermal resistance Junction-ambient. max.	100	$^\circ\text{C/W}$

## 4 Pin connection

**Figure 2. Pin connection**



**Table 4. Pin functions**

No	Function	Description
1	COMP	This pin is the error amplifier output and is made available for loop compensation.
2	V <sub>FB</sub>	This is the inverting input of the error amplifier. It is normally connected to the switching power supply output through a resistor divider.
3	I <sub>SENSE</sub>	A voltage proportional to inductor current is connected to this input. The PWM uses this information to terminate the output switch conduction.
4	R <sub>T</sub> /C <sub>T</sub>	The oscillator frequency and maximum output duty cycle are programmed by connecting resistor RT to Vref and capacitor CT to ground. Operation to 500 kHz is possible.
5	GROUND	This pin is the combined control circuitry and power ground.
6	OUTPUT	This output directly drives the gate of a power MOSFET. Peak currents up to 1A are sourced and sunk by this pin.
7	V <sub>CC</sub>	This pin is the positive supply of the control IC.
8	V <sub>ref</sub>	This is the reference output. It provides charging current for capacitor CT through resistor RT.

## 5 Electrical characteristics

Maximum package power dissipation limits must be respected; low duty cycle pulse techniques are used during test maintain  $T_J$  as close to  $T_A$  as possible.

Unless otherwise stated, these specifications apply for -  $T_A = 22 \pm 3^\circ\text{C}$ ,  $V_i = 15 \text{ V}$ , Adjust  $V_i$  above the start threshold before setting at 15 V;  $R_T = 10 \text{ k}\Omega$ ;  $C_T = 3.3 \text{ nF}$ .

**Table 5. Electrical characteristics**

Symbol	MIL-STD-883 test method	Parameter	Test conditions	Values		Unit
				Min.	Max.	
<b>Reference section</b>						
$V_{\text{REF}}$		Output voltage	$V_i = 15 \text{ V}^{(1)}$ ; $R_T = 10 \text{ k}\Omega$ ; $C_T = 3.3 \text{ nF}$ , $I_o = 1 \text{ mA}$	4.95	5.05	V
$\Delta V_{\text{REF\_LINE}}$		Line regulation	$12 \text{ V} \leq V_i \leq 25 \text{ V}$ , $R_T = 10 \text{ k}\Omega$ ; $C_T = 3.3 \text{ nF}$		0.02	V
$\Delta V_{\text{REF\_LOAD}}$		Load regulation	$V_i = 15 \text{ V}^{(1)}$ ; $R_T = 10 \text{ k}\Omega$ ; $C_T = 3.3 \text{ nF}$ ,		25	V
$I_{\text{SC}}$	3011	Output short circuit	$1 \leq I_o \leq 20 \text{ mA}$	-0.18	-0.03	A
<b>Oscillator section</b>						
$f_{\text{OSC}}$		Frequency for ST1843	$V_i = 15 \text{ V}^{(1)}$ ; $R_T = 10 \text{ k}\Omega$ ; $C_T = 3.3 \text{ nF}$ ,	49	55	kHz
		Frequency for ST1845	$1 \leq I_o \leq 20 \text{ mA}$	24.5	27.5	kHz
$\Delta f_{\text{OSC}}/\Delta v$		Frequency change with voltage	$12 \text{ V} \leq V_i \leq 25 \text{ V}$ ; $R_T = 10 \text{ k}\Omega$ ; $C_T = 3.3 \text{ nF}$	-	1	%
$I_{\text{dischg}}$		Discharge current	$V_i = 15 \text{ V}^{(1)}$ ; $R_T = 10 \text{ k}\Omega$ ; $C_T = 3.3 \text{ nF}$ , $1 \leq I_o \leq 20 \text{ mA}$ , $V_{\text{OSC}} = 2 \text{ V}$	7.8 7.5	8.8 8.8	mA mA
<b>Error amp section</b>						
$V_2$		Input voltage	$V_i = 15 \text{ V}^{(1)}$ ; $R_T = 10 \text{ k}\Omega$ ; $C_T = 3.3 \text{ nF}$ , $V_{\text{PIN1}} = 2.5 \text{ V}$	2.45	2.55	V
$I_b$	4001	Input bias current	$V_i = 15 \text{ V}^{(1)}$ ; $R_T = 10 \text{ k}\Omega$ ; $C_T = 3.3 \text{ nF}$ , $V_{\text{FB}} = 5 \text{ V}$	-1		mA
$A_{\text{VOL}}$		$A_{\text{VOL}}$	$V_i = 15 \text{ V}^{(1)}$ ; $R_T = 10 \text{ k}\Omega$ ; $C_T = 3.3 \text{ nF}$ , $2 \text{ V} \leq V_o \leq 4 \text{ V}$	65		dB
PSRR	4003	Power supply rejec. ratio	$12 \text{ V} \leq V_i \leq 25 \text{ V}$ ; $R_T = 10 \text{ k}\Omega$ ; $C_T = 3.3 \text{ nF}$	60		dB
$I_{o\_sink}$		Output sink current	$V_i = 15 \text{ V}^{(1)}$ ; $R_T = 10 \text{ k}\Omega$ ; $C_T = 3.3 \text{ nF}$ , $V_{\text{PIN2}} = 2.7 \text{ V}$ , $V_{\text{PIN1}} = 1.1 \text{ V}$	2		mA
$I_{o\_source}$		Output source current	$V_i = 15 \text{ V}^{(1)}$ ; $R_T = 10 \text{ k}\Omega$ ; $C_T = 3.3 \text{ nF}$ , $V_{\text{PIN2}} = 2.2 \text{ V}$ , $V_{\text{PIN1}} = 5 \text{ V}$		-0.5	mA

**Table 5. Electrical characteristics (continued)**

Symbol	MIL-STD-883 test method	Parameter	Test conditions	Values		Unit
				Min.	Max.	
$V_{OH}$		$V_{OUT}$ high	$V_I = 15V^{(1)}$ ; $R_T = 10k\Omega$ ; $C_T = 3.3nF$ , $V_{PIN2} = 2.3V$ , $R_L = 15k\Omega$ to GND	5		V
$V_{OL}$		$V_{OUT}$ low	$V_I = 15V^{(1)}$ ; $R_T = 10k\Omega$ ; $C_T = 3.3nF$ , $V_{PIN2} = 2.3V$ , $R_L = 15k\Omega$ to GND		1.1	V
<b>Current sense section</b>						
$G_V$	4004	Gain	$V_I = 15V^{(1)}$ ; $R_T = 10k\Omega$ ; $C_T = 3.3nF$ , (2) (3)	2.85	3.15	V/V
$V_3$		Maximum input signal	$V_I = 15V^{(1)}$ ; $R_T = 10k\Omega$ ; $C_T = 3.3nF$ , $V_{PIN1} = 2.3V^{(2)}$	0.9	1.1	V
SVR		Supply voltage rejection	$12 \leq V_I \leq 25V$ ; $R_T = 10k\Omega$ ; $C_T = 3.3nF^{(1)}$	60		dB
$I_b$	4001	Input bias current	$V_I = 15V^{(1)}$ ; $R_T = 10k\Omega$ ; $C_T = 3.3nF$	-10		mA
$D_O$	3003	Delay to output	$V_I = 15V^{(1)}$ ; $R_T = 10k\Omega$ ; $C_T = 3.3nF$		300	ns
<b>Output section</b>						
$V_{OL1}$	3007	Output low level	$V_I = 15V^{(1)}$ ; $R_T = 10k\Omega$ ; $C_T = 3.3nF$ ; $I_{SINK} = 20mA$		0.4	V
$V_{OL2}$			$V_I = 15V^{(1)}$ ; $R_T = 10k\Omega$ ; $C_T = 3.3nF$ ; $I_{SINK} = 200mA$		2.2	V
$V_{OH1}$	3006	Output high level	$V_I = 15V^{(1)}$ ; $R_T = 10k\Omega$ ; $C_T = 3.3nF$ ; $I_{SOURCE} = 20mA$	13		V
$V_{OH2}$			$V_I = 15V^{(1)}$ ; $R_T = 10k\Omega$ ; $C_T = 3.3nF$ ; $I_{SOURCE} = 200mA$	12		V
$V_{OLS}$		UVLO saturation	$V_I = 6V^{(1)}$ ; $R_T = 10k\Omega$ ; $C_T = 3.3nF$ ; $I_{SINK} = 1mA$		1.1	V
$t_r$	3004	Rise time	$V_I = 15V^{(1)}$ ; $R_T = 10k\Omega$ ; $C_T = 3.3nF$ ; $C_L = 1nF$		150	ns
$t_f$		Fall time			150	ns
<b>Under-voltage lockout section</b>						
$V_{TH}$		Start threshold	$V_I = 15V^{(1)}$ ; $R_T = 10k\Omega$ ; $C_T = 3.3nF$	7.8	9	V
$V_{MIN}$		Min operating voltage after turn-on	$V_I = 15V^{(1)}$ ; $R_T = 10k\Omega$ ; $C_T = 3.3nF$	7	8.2	V
$DC_{MAX}$		Max duty cycle for ST1843	$V_I = 15V^{(1)}$ ; $R_T = 10k\Omega$ ; $C_T = 3.3nF$	47	50	%
		Max duty cycle for ST1845		94	100	%
$DC_{MIN}$		Min duty cycle	$V_I = 15V^{(1)}$ ; $R_T = 10k\Omega$ ; $C_T = 3.3nF$		0	%
<b>Total standby current</b>						
$I_{st}$		Start-up current	$V_I = 15V^{(1)}$ ; $R_T = 10k\Omega$ ; $C_T = 3.3nF$		0.5	mA

**Table 5. Electrical characteristics (continued)**

Symbol	MIL-STD-883 test method	Parameter	Test conditions	Values		Unit
				Min.	Max.	
I <sub>i</sub>	3005	Operating supply current	V <sub>I</sub> = 15V <sup>(1)</sup> ; R <sub>T</sub> = 10kΩ; C <sub>T</sub> = 3.3nF V <sub>PIN2</sub> = V <sub>PIN3</sub> = 0V		17	mA
V <sub>iz</sub>		Zener voltage	V <sub>I</sub> = 15V <sup>(1)</sup> ; R <sub>T</sub> = 10kΩ; C <sub>T</sub> = 3.3nF I <sub>i</sub> = 25mA	30		V

1. Adjust V<sub>i</sub> above the start threshold before setting at 15V2. Parameter measured at trip point of latch with V<sub>PIN2</sub> = 0.

3. Gain defined as:

$$A = \frac{\Delta V_{PIN1}}{\Delta V_{PIN3}}; 0 \leq \Delta V_{PIN3} \leq 0.8V$$

## 6 Radiation characteristics

### 6.1 Total dose

The total dose results are provided in the following table:

**Table 6. Total dose performance**

Device	Total dose
ST1843HR	50 krad (Si)
ST1845HR	100 krad (Si)

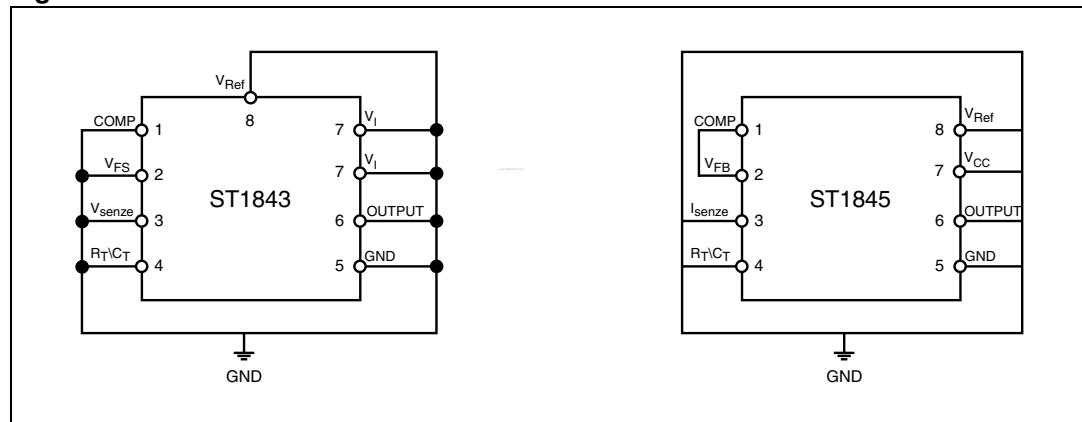
These results are obtained on the following conditions:

#### 6.1.1 Bias conditions and total dose level for total dose radiation testing

Continuous bias shall be applied during irradiation testing as specified below.

The total dose level applied shall be as specified in the component type variant information here in or in purchaser order.

**Figure 3. Unbias conditions**



### 6.1.2 Electrical measurements for total dose radiation testing

Prior to irradiation testing the devices shall have successfully met room temperature electrical measurements specified herein.

Unless otherwise stated the measurements shall be performed at  $T_A = +22 \pm 3^\circ\text{C}$

The test methods and test conditions shall be as per the corresponding test defined in electrical measurements at room temperature. The parameters to be measured during and on completion of irradiation testing are shown below.

**Table 7. Electrical parameter during irradiation testing**

Symbol	Parameter	Test conditions	Values		Unit
			Min.	Max.	
<b>Reference section</b>					
$V_{\text{REF}}$	Output voltage for <b>ST1843</b>	$V_I = 15V; R_T = 10k\Omega; C_T = 3.3nF; I_o = 1mA$	4.95	5.15	V
	Output voltage for <b>ST1845</b>		4.85	5.15	
$\Delta V_{\text{REF\_LINE}}$	Line regulation	$12V \leq V_i \leq 25V, R_T = 10k\Omega; C_T = 3.3nF$		0.02	V
$\Delta V_{\text{REF\_LOAD}}$	Load regulation	$V_I = 15V; R_T = 10k\Omega; C_T = 3.3nF, 1 \leq I_o \leq 20mA$		0.025	V
$I_{\text{SC}}$	Output short circuit current	$V_I = 15V; R_T = 10k\Omega; C_T = 3.3nF$	-0.18	-0.03	A
<b>Oscillator section</b>					
$F_{\text{osc}}$	Frequency	$V_I = 15V; R_T = 10k\Omega; C_T = 3.3nF$	49	65	kHz
$\Delta F_{\text{osc}} / \Delta V$	Frequency change with voltage	$12V \leq V_i \leq 25V, R_T = 10k\Omega; C_T = 3.3nF$	-1	1	%
$I_{\text{DISCHG}}$	Discharge current	$V_I = 15V; R_T = 10k\Omega; C_T = 3.3nF; V_{\text{osc}} = 2V$	0.0078	0.0088	A
<b>Error amp section</b>					
$V_2$	Input voltage for <b>ST1843</b>	$V_I = 15V; R_T = 10k\Omega; C_T = 3.3nF; \text{VPIN1} = 2.5V$	2.45	2.6	V
	Input voltage for <b>ST1845</b>		2.45	2.55	
$I_b$	Input bias current <b>ST1843</b>	$V_I = 15V; R_T = 10k\Omega; C_T = 3.3nF; V_{FB} = 5V$	-2.75		$\mu\text{A}$
	Input bias current <b>ST1845</b>		-2.8		
$AVOL$	AVOL for <b>ST1843</b>	$V_I = 15V; R_T = 10k\Omega; C_T = 3.3nF; 2V \leq V_o \leq 4V$	60		dB
	AVOL for <b>ST1845</b>		62		
$PSRR$	Power supply rejection ratio	$12V \leq V_i \leq 25V, R_T = 10k\Omega; C_T = 3.3nF$	60		dB
$IO_{\text{SINK}}$	Output sink current	$V_I = 15V; R_T = 10k\Omega; C_T = 3.3nF; \text{VPIN2} = 2.7V; \text{VPIN1} = 1.1V$	2		mA
$IO_{\text{SOURCE}}$	Output source current	$V_I = 15V; R_T = 10k\Omega; C_T = 3.3nF; \text{VPIN2} = 2.3V; \text{VPIN1} = 5V$		-0.5	mA
$V_{\text{OH}}$	VOUT high	$V_I = 15V; R_T = 10k\Omega; C_T = 3.3nF; \text{VPIN2} = 2.3V; R_L = 15k\Omega \text{ to GND}$	5		V
$V_{\text{OL}}$	VOUT low	$V_I = 15V; R_T = 10k\Omega; C_T = 3.3nF; \text{VPIN2} = 2.3V; R_L = 15k\Omega \text{ to pin}$		1.1	V

**Table 7. Electrical parameter during irradiation testing (continued)**

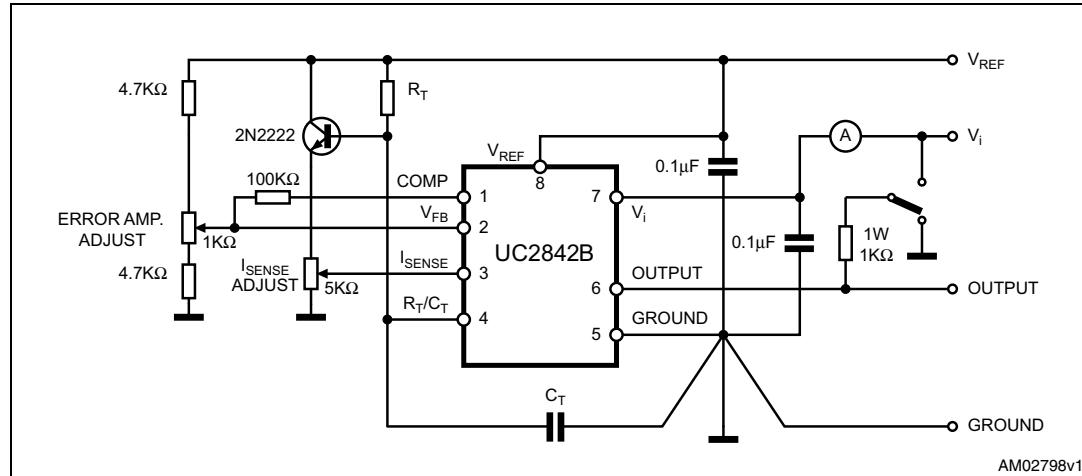
Symbol	Parameter	Test conditions	Values		Unit
			Min.	Max.	
<b>Current sense section</b>					
G <sub>V</sub>	Gain	V <sub>I</sub> = 15V; R <sub>T</sub> = 10kΩ; C <sub>T</sub> = 3.3nF;	2.85	3.15	V/V
V <sub>3</sub>	Maximum input signal	V <sub>I</sub> = 15V; R <sub>T</sub> = 10kΩ; C <sub>T</sub> = 3.3nF; VPIN1 = 2.3V;	0.9	1.1	V
SVR	Supply voltage rejection	12V ≤ V <sub>I</sub> ≤ 25V; R <sub>T</sub> = 10kΩ; C <sub>T</sub> = 3.3nF;	60		dB
I <sub>b</sub>	Input bias current <b>ST1843</b>	V <sub>I</sub> = 15V; R <sub>T</sub> = 10kΩ; C <sub>T</sub> = 3.3nF;	-50		μA
	Input bias current <b>ST1845</b>		-45		
D <sub>O</sub>	Delay to output	V <sub>I</sub> = 15V; R <sub>T</sub> = 10kΩ; C <sub>T</sub> = 3.3nF;		300	ns
<b>Output section</b>					
V <sub>OL1</sub>	Output low level	V <sub>I</sub> = 15V; R <sub>T</sub> = 10kΩ; C <sub>T</sub> = 3.3nF; I <sub>SINK</sub> = 20mA		0.4	V
V <sub>OL2</sub>	Output low level	V <sub>I</sub> = 15V; R <sub>T</sub> = 10kΩ; C <sub>T</sub> = 3.3nF; I <sub>SINK</sub> = 200mA		2.2	V
V <sub>OH1</sub>	Output high level	V <sub>I</sub> = 15V; R <sub>T</sub> = 10kΩ; C <sub>T</sub> = 3.3nF; I <sub>SOURCE</sub> = 20mA	13		V
V <sub>OH2</sub>	Output high level	V <sub>I</sub> = 15V; R <sub>T</sub> = 10kΩ; C <sub>T</sub> = 3.3nF; I <sub>SOURCE</sub> = 200mA	12		V
V <sub>OLS</sub>	UVLO saturation	V <sub>I</sub> = 15V; R <sub>T</sub> = 10kΩ; C <sub>T</sub> = 3.3nF; I <sub>SINK</sub> = 1mA		1.1	V
T <sub>R</sub>	Rise time	V <sub>I</sub> = 15V; R <sub>T</sub> = 10kΩ; C <sub>T</sub> = 3.3nF; C <sub>L</sub> = 1nF		180	ns
T <sub>F</sub>	Fall time	V <sub>I</sub> = 15V; R <sub>T</sub> = 10kΩ; C <sub>T</sub> = 3.3nF; C <sub>L</sub> = 1nF		180	ns
<b>Under-voltage lockout section</b>					
V <sub>TH</sub>	Start threshold for <b>ST1843</b>	V <sub>I</sub> = 15V; R <sub>T</sub> = 10kΩ; C <sub>T</sub> = 3.3nF;	7.8	9.5	V
	Start threshold for <b>ST1845</b>		7.8	10.5	
V <sub>MIN</sub>	Min operating voltage after turn-on for <b>ST1843</b>	V <sub>I</sub> = 15V; R <sub>T</sub> = 10kΩ; C <sub>T</sub> = 3.3nF;	7	8.6	V
	Min operating voltage after turn-on for <b>ST1845</b>		7	9	
DCMAX	Max duty cycle	V <sub>I</sub> = 15V; R <sub>T</sub> = 10kΩ; C <sub>T</sub> = 3.3nF;	94	100	%
DCMIN	Min duty cycle	V <sub>I</sub> = 15V; R <sub>T</sub> = 10kΩ; C <sub>T</sub> = 3.3nF;		0	%
<b>Total stand-by current</b>					
I <sub>ST</sub>	Start-up current	V <sub>I</sub> = 6.5V; R <sub>T</sub> = 10kΩ; C <sub>T</sub> = 3.3nF;		0.5	mA
I <sub>i</sub>	Operating supply current	V <sub>I</sub> = 15V; R <sub>T</sub> = 10kΩ; C <sub>T</sub> = 3.3nF; VPIN2 = VPIN3 = 0V		17	mA
V <sub>iz</sub>	Zener voltage	V <sub>I</sub> = 15V; R <sub>T</sub> = 10kΩ; C <sub>T</sub> = 3.3nF; I <sub>i</sub> = 25mA	30		V

### 6.1.3 Heavy Ions

Both devices have been tested SEL free at 120 MeV/cm<sup>2</sup>/mg at 125°C

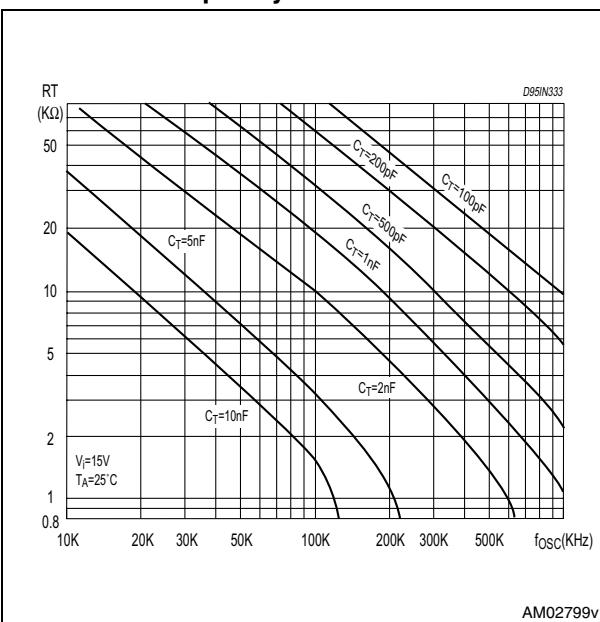
## 7 Test circuit

**Figure 4.** Open loop test circuit



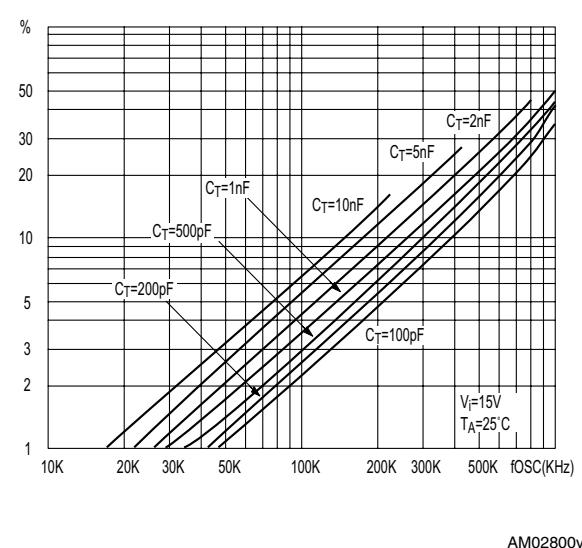
High peak currents associated with capacitive loads necessitate careful grounding techniques. Timing and bypass capacitors should be connected close to pin 5 in a single point ground. The transistor and 5 k $\Omega$  potentiometer are used to sample the oscillator waveform and apply an adjustable ramp to pin 3.

**Figure 5.** Timing resistor vs. oscillator frequency



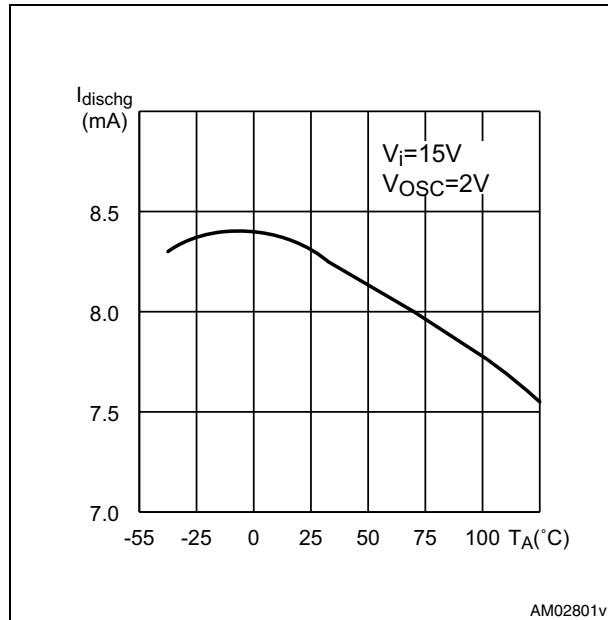
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**Figure 6.** Output dead-time vs. oscillator frequency

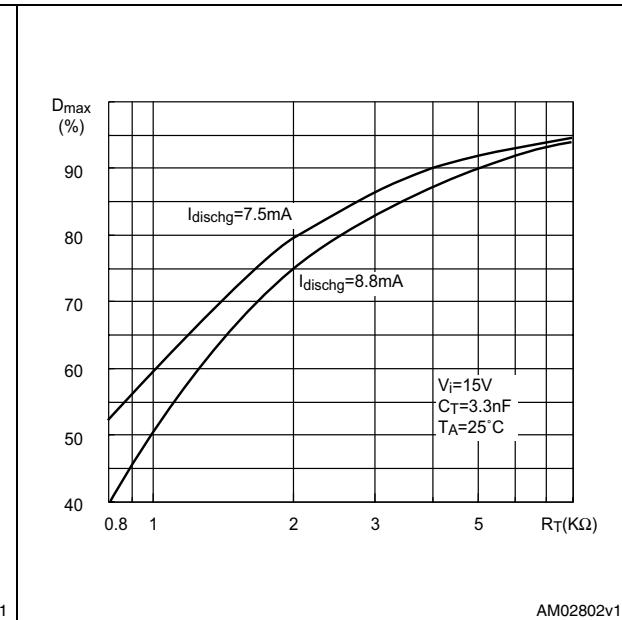


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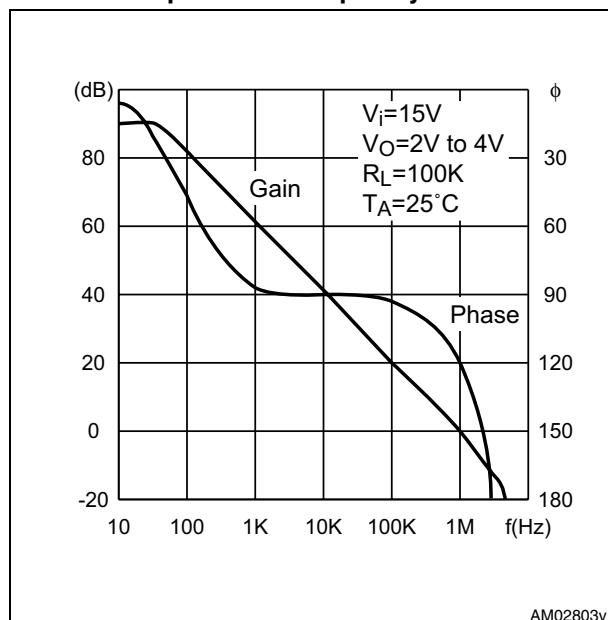
**Figure 7. Oscillator discharge current vs. temperature**



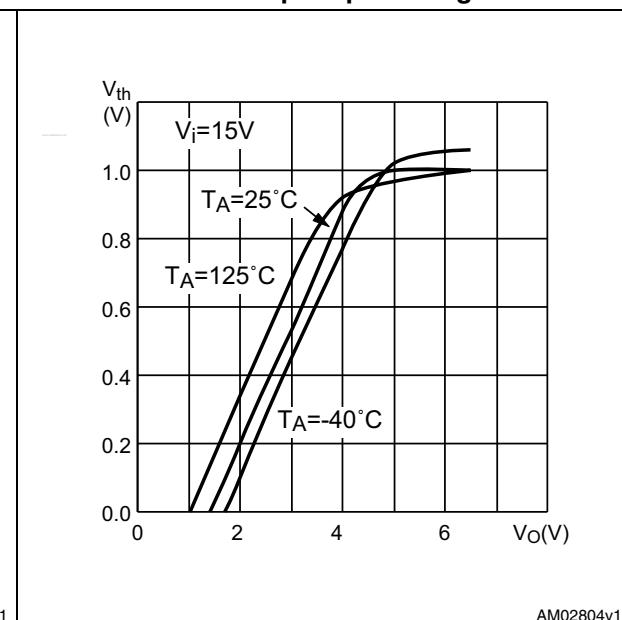
**Figure 8. Maximum output duty cycle vs. timing resistor**



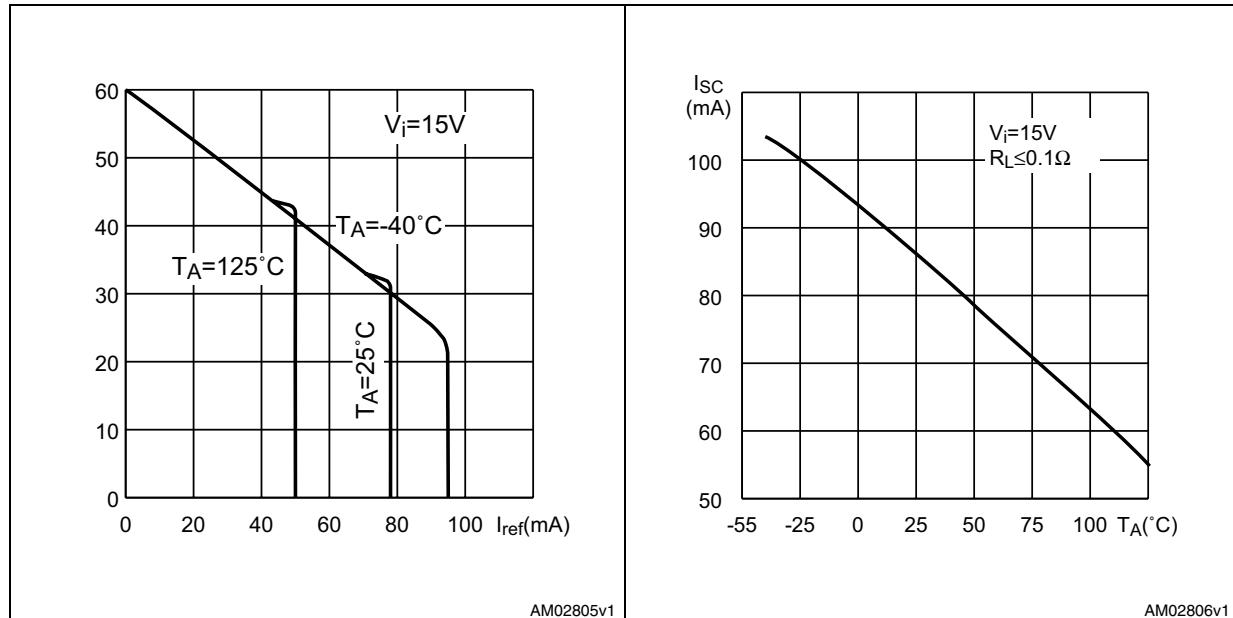
**Figure 9. Error amp open-loop gain and phase vs. frequency**



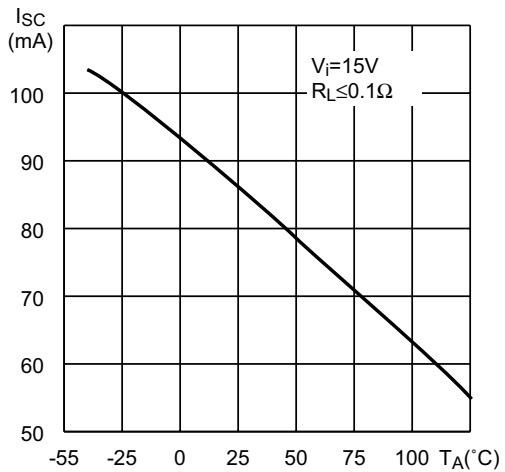
**Figure 10. Current sense input threshold vs. error amp output voltage**



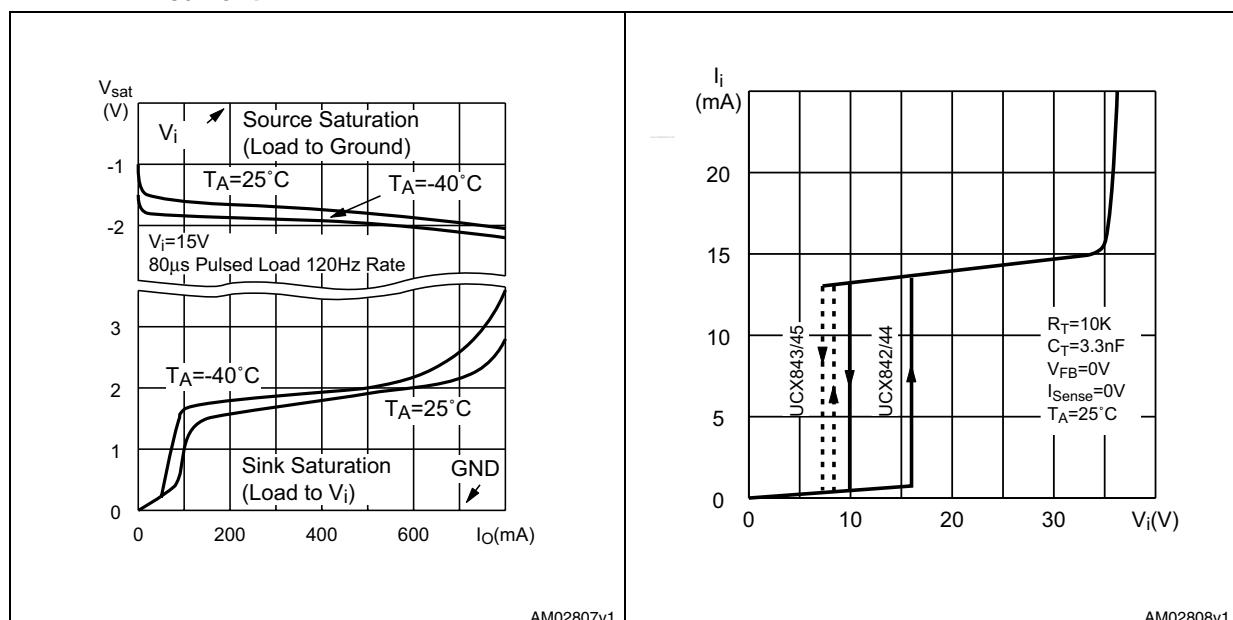
**Figure 11. Reference voltage change vs. source current**



**Figure 12. Reference short circuit current vs. temperature**



**Figure 13. Output saturation voltage vs. load current**



**Figure 14. Supply current vs. supply voltage**

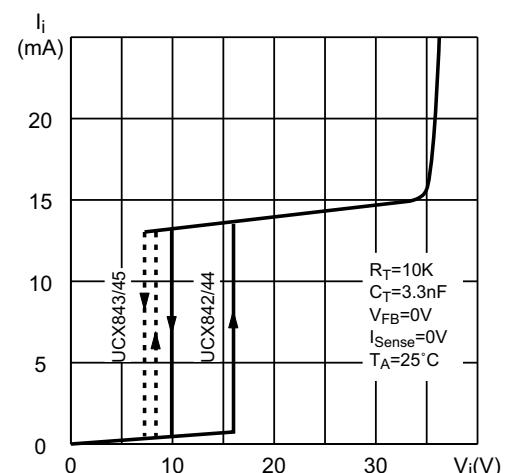


Figure 15. Output waveform

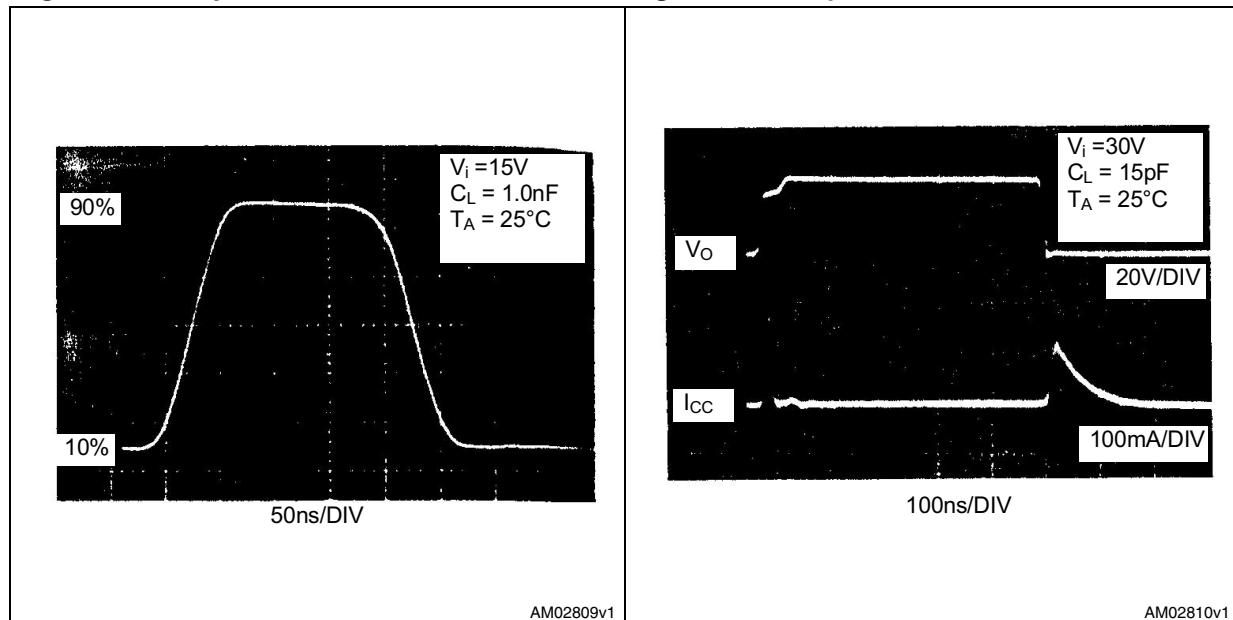


Figure 16. Output cross conduction

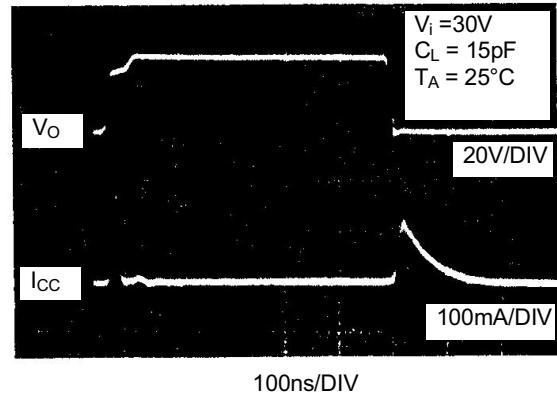
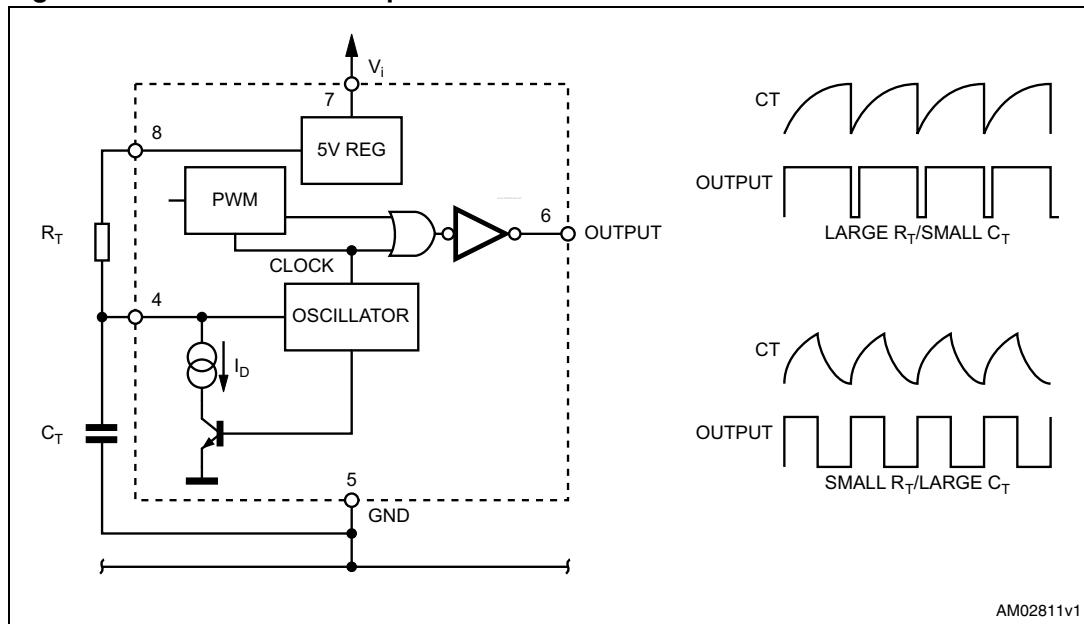
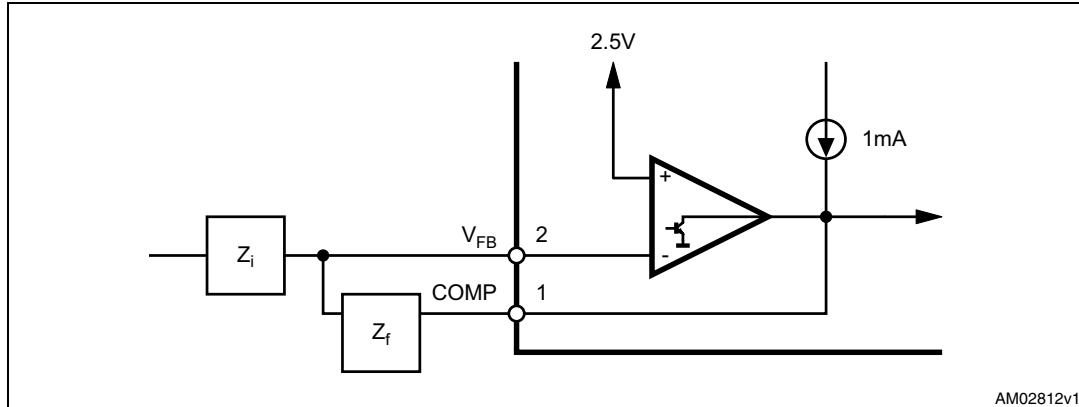
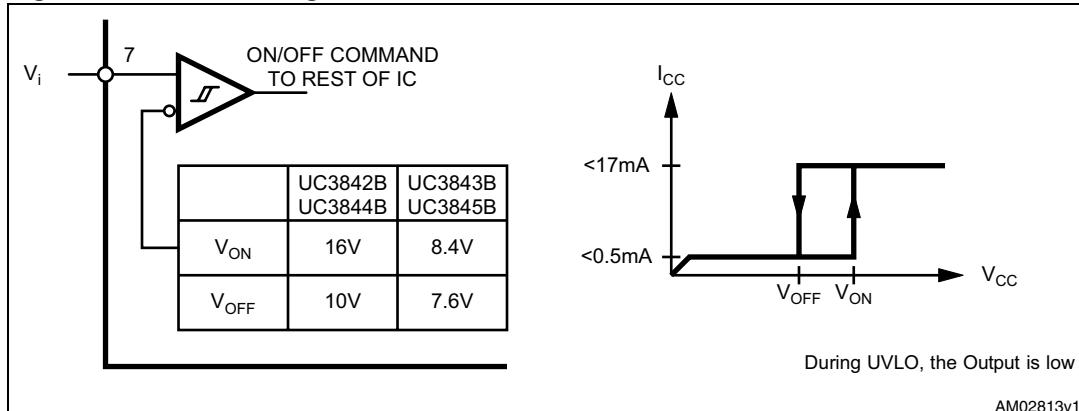
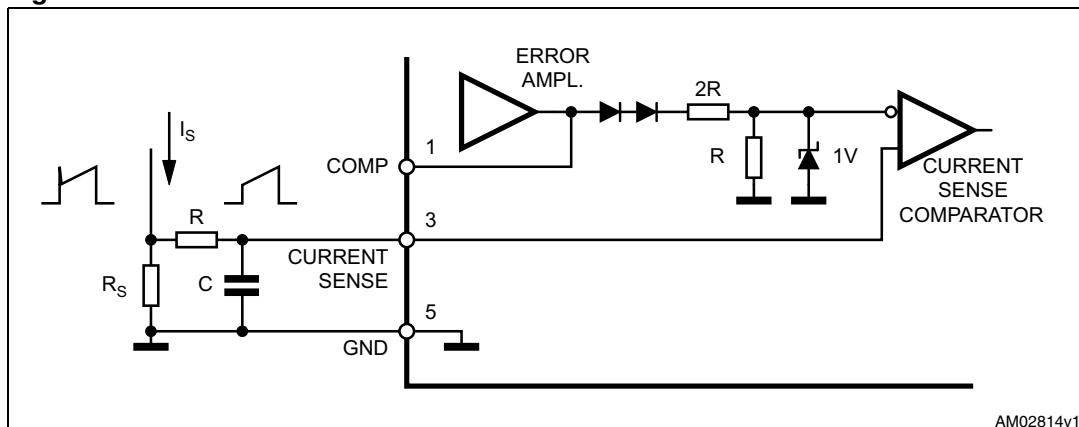


Figure 17. Oscillator and output waveforms



**Figure 18. Error amp configuration****Figure 19. Under voltage lockout****Figure 20. Current sense circuit**

Peak current ( $I_s$ ) is determined by the formula:

$$I_{Smax} \approx \frac{1.0V}{R_S}$$

A small RC filter may be required to suppress switch transients.

Figure 21. Slope compensation techniques

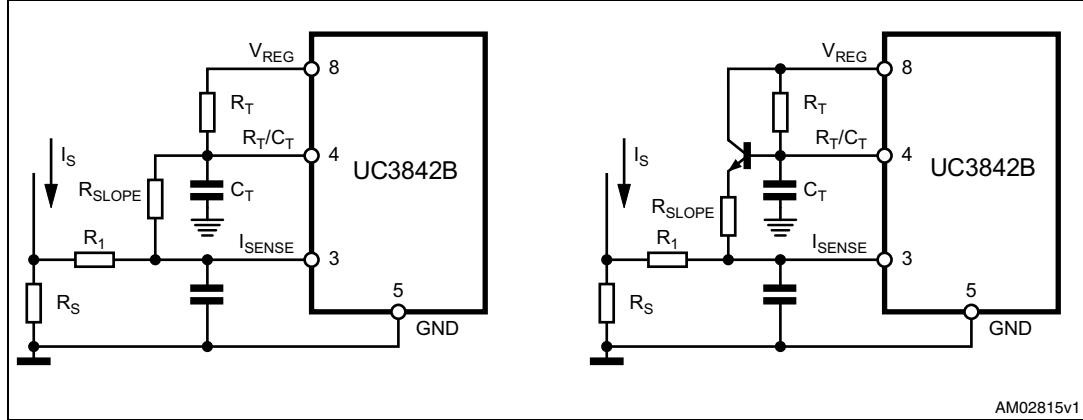
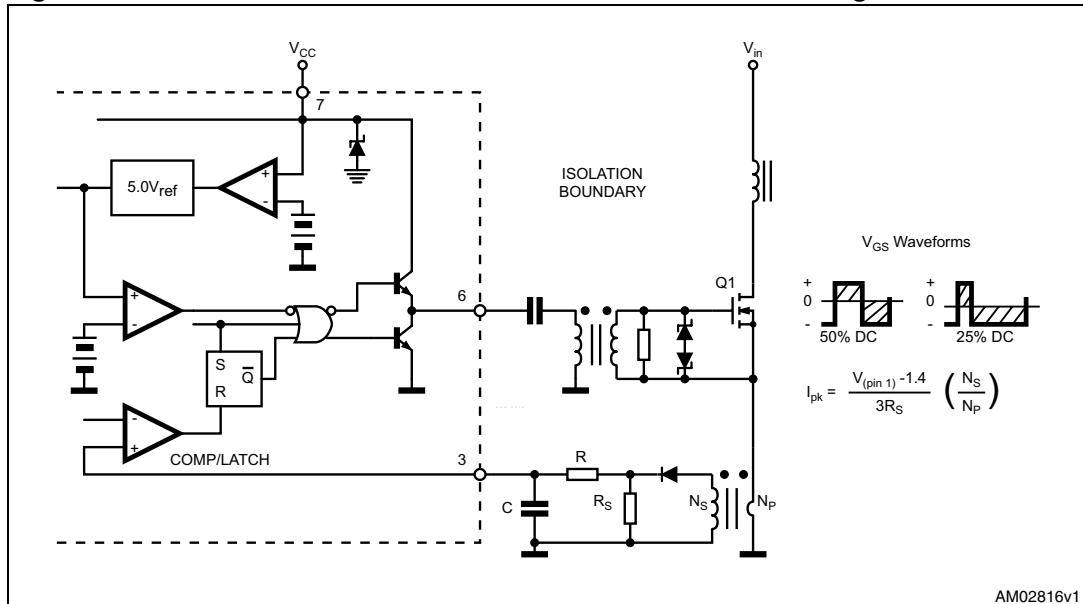


Figure 22. Isolated MOSFET drive and current transformer sensing



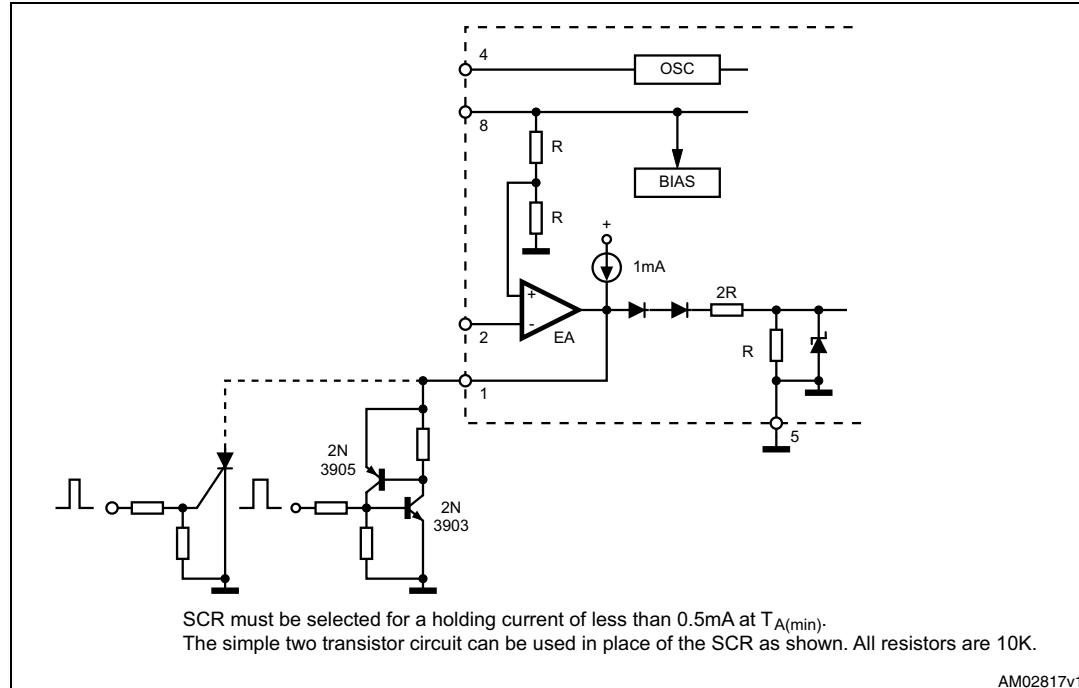
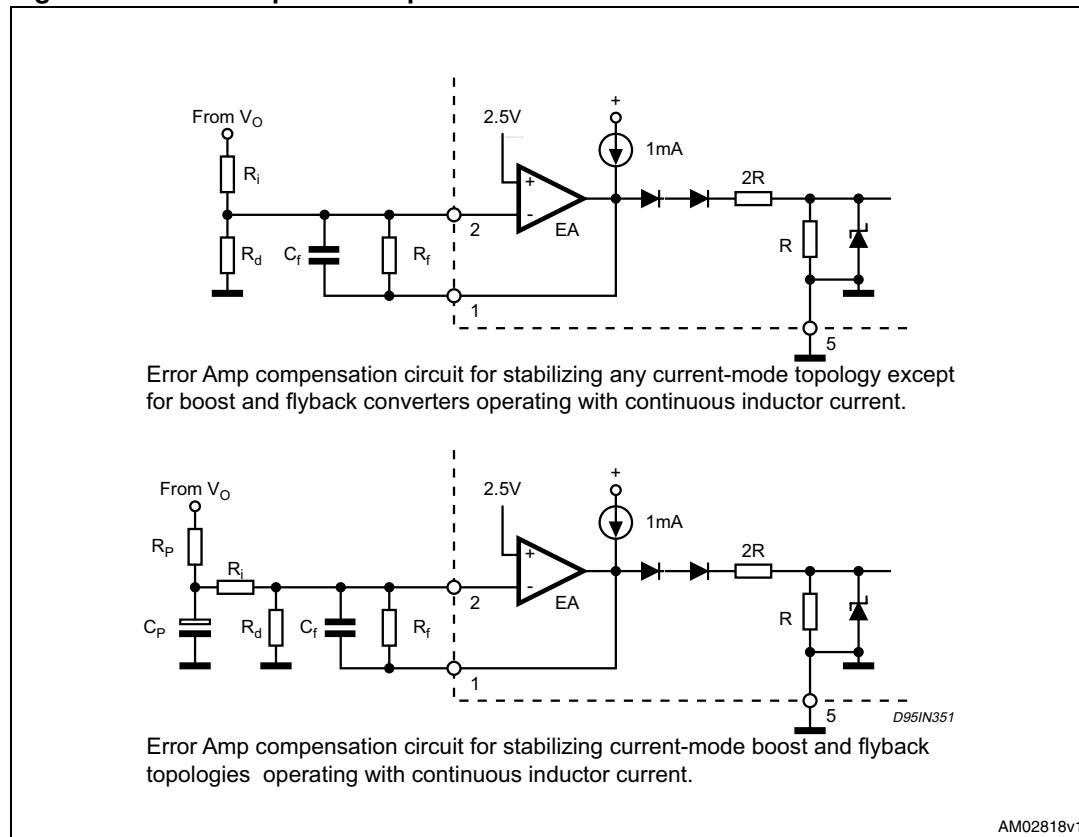
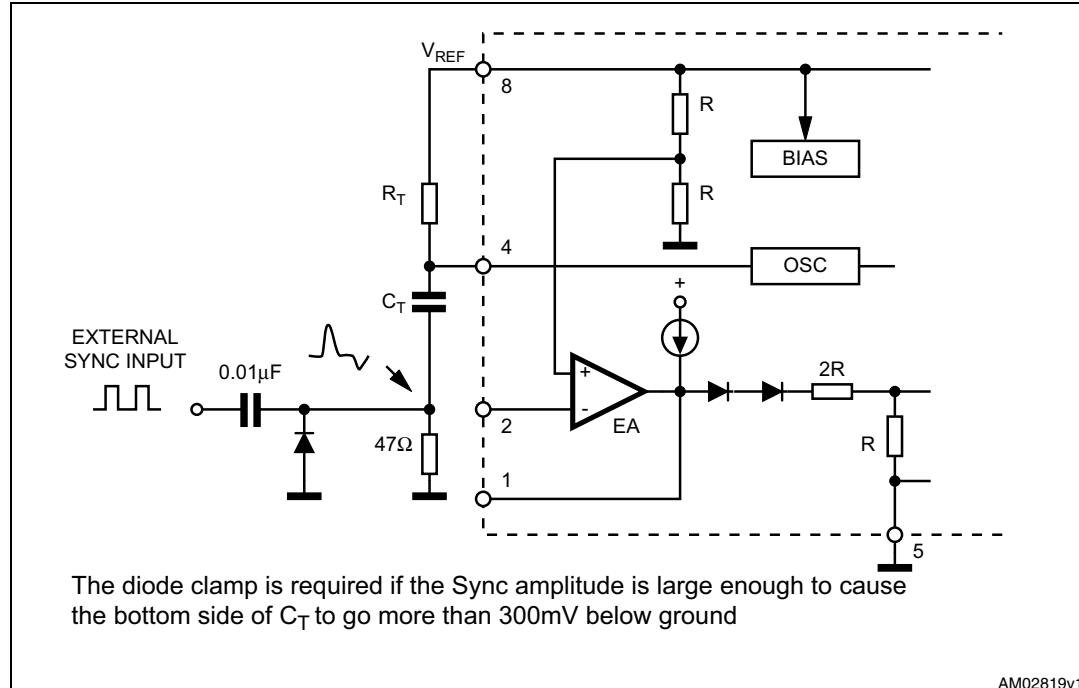
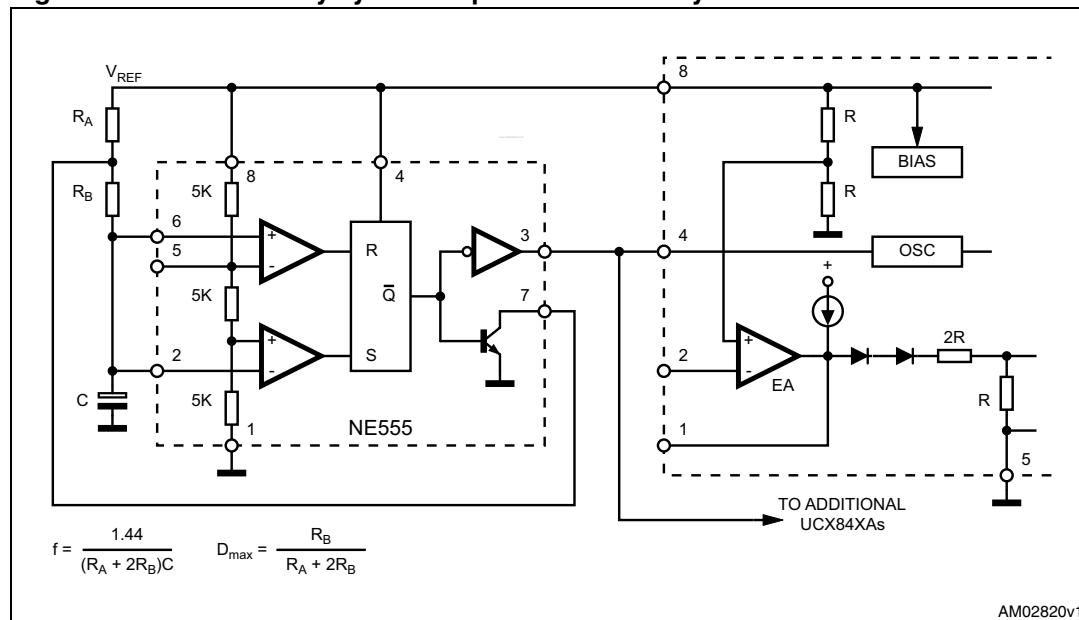
**Figure 23. Latched shutdown****Figure 24. Error amplifier compensation**

Figure 25. External clock synchronization



AM02819v1

Figure 26. External duty cycle clamp and multi unit synchronization



AM02820v1

Figure 27. Soft-start circuit

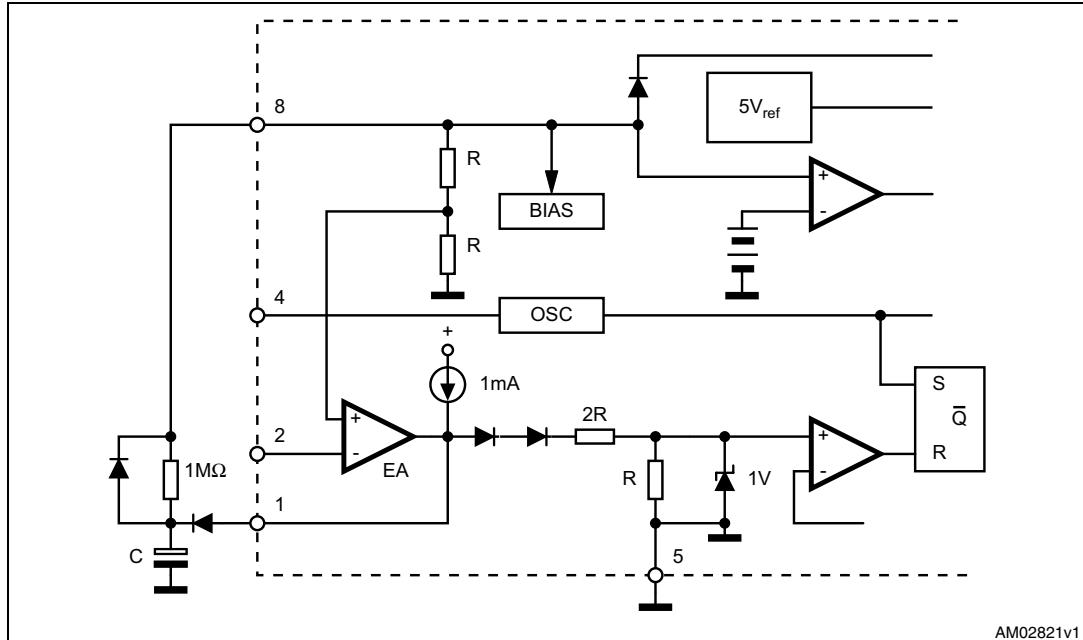
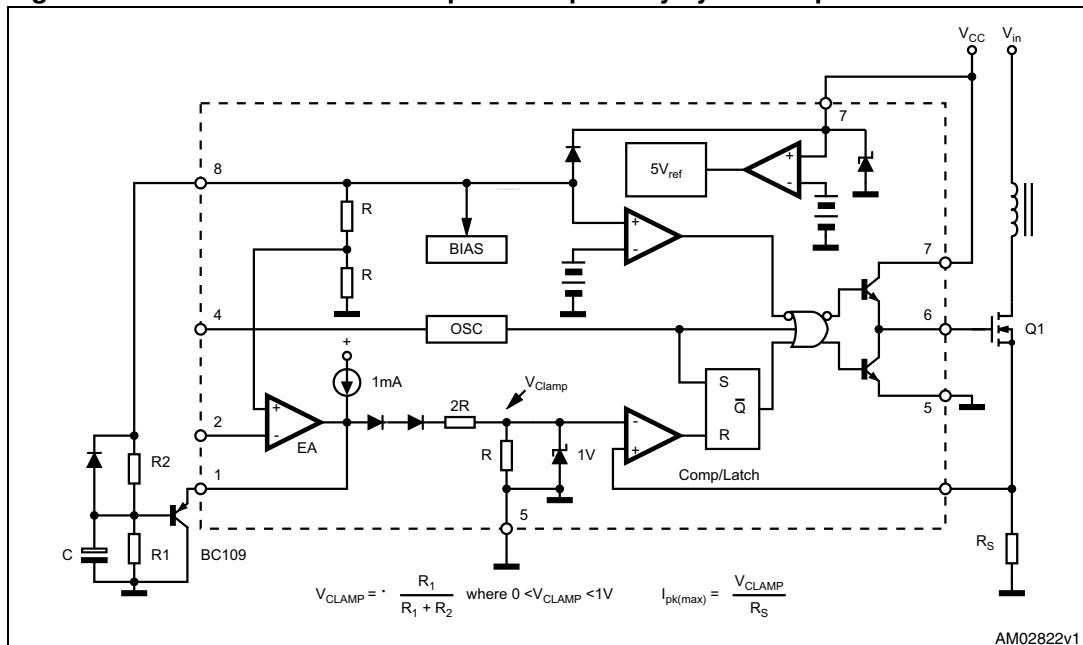


Figure 28. Soft-start and error amplifier output duty cycle clamp



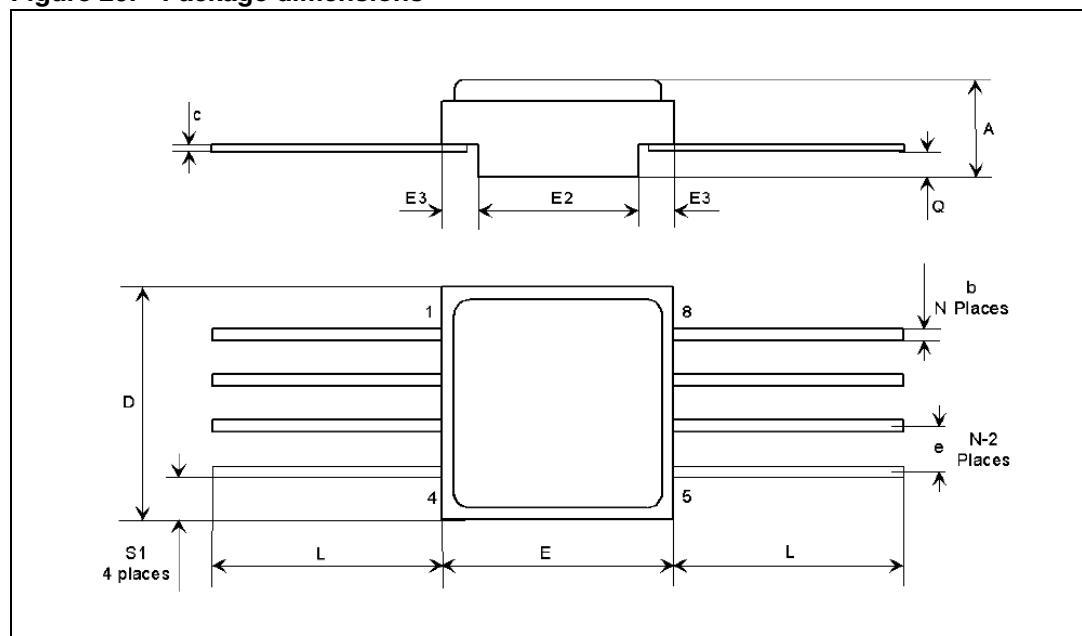
## 8 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com).  
ECOPACK is an ST trademark.

**Table 8. Flat-8 mechanical data**

Dim.	mm.			inch		
	Min	Typ	Max	Min	Typ	Max
A	2.24	2.44	2.64	0.088	0.096	0.104
b	0.38	0.43	0.48	0.015	0.017	0.019
c	0.10	0.13	0.16	0.004	0.005	0.006
D	6.35	6.48	6.61	0.250	0.255	0.260
E	6.35	6.48	6.61	0.250	0.255	0.260
E2	4.32	4.45	4.58	0.170	0.175	0.180
E3	0.88	1.01	1.14	0.035	0.040	0.045
e		1.27			0.050	
L	6.51	-	7.38	0.256	-	0.291
Q	0.66	0.79	0.92	0.026	0.031	0.036
S1	0.92	1.12	1.32	0.036	0.044	0.052
N	08			08		

**Figure 29. Package dimensions**



## 9 Ordering information

**Table 9. Ordering information**

Order codes	Quality level	EPPL	Package	Lead finish	Marking	Packing
ST1843K1	Engineering Model	-	Flat-8	Gold	ST1843K1	Strip pack
ST1843FKG	According to ESCC	Target	Flat-8	Gold	ST1843FKG	Strip pack
ST1845K1	Engineering Model	-	Flat-8	Gold	ST1845K1	Strip pack
ST1845RKG	According to ESCC	Target	Flat-8	Gold	ST1845RKG	Strip pack

## 10 Revision history

**Table 10. Document revision history**

Date	Revision	Changes
12-Sep-2011	1	First revision

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